

Application No.	Applicant(s)
10/071,370	BAYNE ET AL.
Examiner	Art Unit
Jon M Lockard	1647

SEARCHED				
Class	Subclass	Date	Examiner	
424	198.1	9/21/2004	JML	
435	69.1			
	252.3			
	320.1			
514	12			
530	350			
	399			
536	23.5			
	24.31			
	·			
			·	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Stic Search of Commercial and Patent Databases: See Attached Search Report	9/17/2004	JML
East Search: Text and Inventors Name Search: See attached Search Report.	9/21/2004	JML
PALM: Inventor's Name Search: See Attached Search Report	9/21/2004	JML
	-	